

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 09/912,221 | Applicant(s)/Patent Under Reexamination HAAS ET AL. | |
| | Examiner Cheukfan Lee | Art Unit 2622 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,373,556 | 04-2002 | Gervais, Michel | 355/75 |
| | B | US-6,208,437 | 03-2001 | Neushul, Stephen | 358/487 |
| | C | US-6,185,011 | 02-2001 | William, Leu | 358/474 |
| | D | US-6,819,457 | 11-2004 | Sheng, Thomas | 358/487 |
| | E | US-6,494,586 | 12-2002 | Huang et al. | 362/27 |
| | F | US-6,567,191 | 05-2003 | Huang, Chih-Wen | 358/487 |
| | G | US-6,519,023 | 02-2003 | Chang, Martin | 355/18 |
| | H | US-5,993,023 | 11-1999 | Lin, Bob | 362/223 |
| | I | US-5,781,311 | 07-1998 | Inoue et al. | 358/475 |
| | J | US-5,574,542 | 11-1996 | Brook, III, Mark G. | 399/380 |
| | K | US-6,177,982 | 01-2001 | Snyder et al. | 355/75 |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.